- **Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs**
- **Dependable Texas Instruments Quality and Reliability**

description

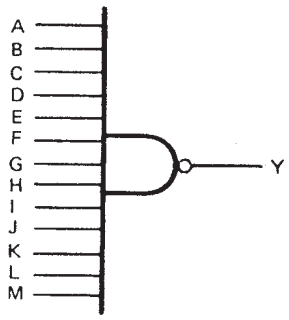
These devices contain a single 13-input NAND gate.

The SN54133 is characterized for operation over the full military temperature range of −55°C to 125°C. The SN74133 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

INPUTS A THRU M	OUTPUT Y
All inputs H	L
One or more inputs L	H

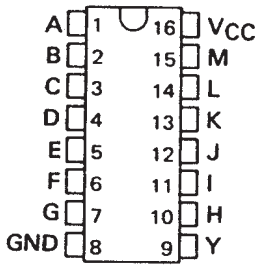
logic diagram



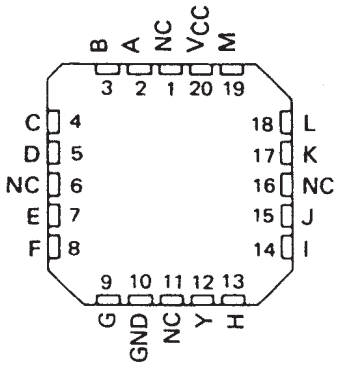
positive logic

$$Y = \overline{A \cdot B \cdot C \cdot D \cdot E \cdot F \cdot G \cdot H \cdot I \cdot J \cdot K \cdot L \cdot M} \text{ or}$$
$$Y = \overline{A} + \overline{B} + \overline{C} + \overline{D} + \overline{E} + \overline{F} + \overline{G} + \overline{H} + \overline{I} + \overline{J} + \overline{K} + \overline{L} + \overline{M}$$

SN54S133 . . . J OR W PACKAGE
SN74S133 . . . D OR N PACKAGE
(TOP VIEW)

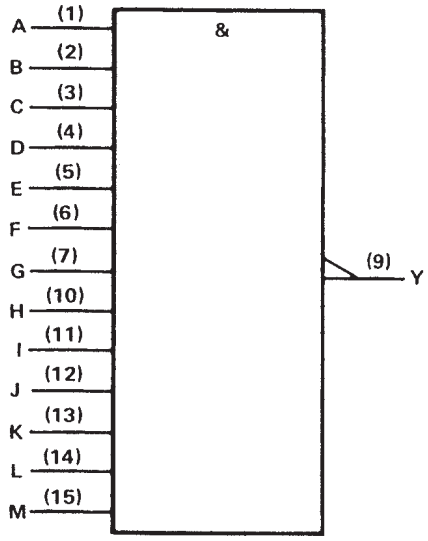


SN54S133 . . . FK PACKAGE
(TOP VIEW)



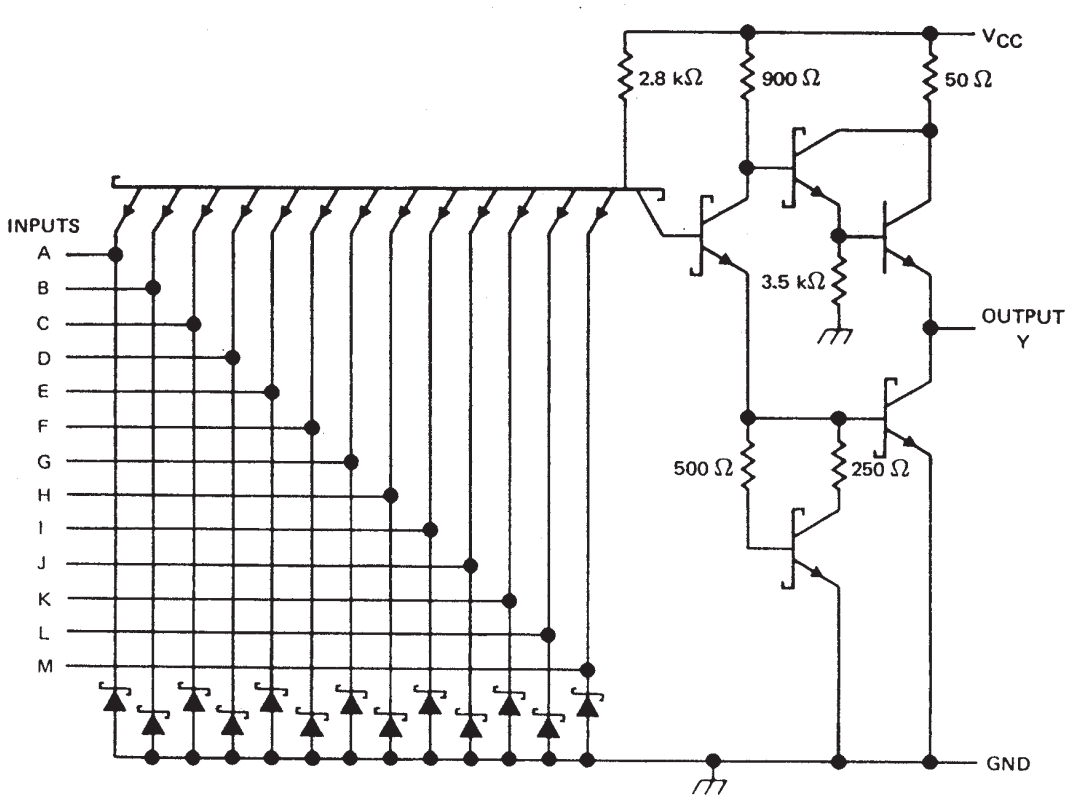
NC - No internal connection

logic symbol†



†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

'S133



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 5.5 V
Operating free-air temperature range: SN54' . . . . . −55°C to 125°C
SN74' . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54S133			SN74S133			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{OH}	High-level output current			−1			−1	mA
I_{OL}	Low-level output current			20			20	mA
T_A	Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †				SN54S133			SN74S133			UNIT
					MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}	V_{CC} = MIN,	I_I = −18 mA					−1.2			−1.2	V
V_{OH}	V_{CC} = MIN,	V_{IL} = 0.8 V,	I_{OH} = −1 mA		2.5	3.4		2.7	3.4		V
V_{OL}	V_{CC} = MIN,	V_{IH} = 2 V,	I_{OL} = 20 mA				0.5			0.5	V
I_I	V_{CC} = MAX,	V_I = 5.5 V					1			1	mA
I_{IH}	V_{CC} = MAX,	V_I = 2.7 V					50			50	μA
I_{IL}	V_{CC} = MAX,	V_I = 0.5 V					−2			−2	mA
I_{OS}§	V_{CC} = MAX				−40		−100	−40		−100	mA
I_{CCH}	V_{CC} = MAX,	V_I = 0 V				3	5		3	5	mA
I_{CCL}	V_{CC} = MAX,	V_I = 4.5 V				5.5	10		5.5	10	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Any	Y	R_L = 280 Ω,	C_L = 15 pF		4	6	ns
t_{PHL}						4.5	7	ns
t_{PLH}			R_L = 280 Ω,	C_L = 50 pF		5.5		ns
t_{PHL}						6.5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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